

<b>Notice of References Cited</b>	Application/Control No. 09/781,730	Applicant(s)/Patent Under Reexamination FARQUHAR ET AL.	
	Examiner John L. Goff	Art Unit 1733	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,374,453	12-1994	Swei et al.	427/226
	B	US-4,590,539	05-1986	Sanjana et al.	361/760
	C	US-3,713,870	01-1973	Kaye, Melvin S.	427/383.1
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Computer-Controlled Optical Testing of High-Density Printec-Circuit Board", 1983, IBM J. Res. Develop. Vol 27, pp. 50-58.
	V	
	W	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.